

Notice of References Cited	Application/Control No. 10/583,263		Applicant(s)/Patent Under Reexamination MARUO ET AL.	
	Examiner DENNIS M. WHITE		Art Unit 1797	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-2004/0131501	07-2004	Maruo et al.	422/091
	B	US-			
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2001343380 A	12-2001	Japan	OMATSU, TAKESHI	
	O					
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Chiang et al, "Combinatorial approach to the edge delamination test for thin film reliability-adaptability and variability" Thin Solid Films, available online December 8, 2004, Volume 476, Issue 2, Pgs. 379-385.
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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